

POLYHEDRON INSPECTION FEEDER AND POLYHEDRON
INSPECTION APPARATUS

ABSTRACT OF THE DISCLOSURE

A supply means 11 for supplying a chip W such as a chip capacitor as an inspection object, a conveying means 12 attached to the supply means 11, and a polyhedron inspection feeder 13 are provided. The polyhedron inspection feeder 13 includes a rotating feed section 41 provided with a groove 50 for rotating the chip W by approximately 180° in a process that the chip W is moved. The conveying means 12 is formed from a belt B and is arranged so that each chip W is moved one by one by receiving the chips W one by one in the perforations 38 formed in the belt B. In the area of the polyhedron inspection feeder 13, four cameras 14-17 take images of the inspection surface of the chip W to detect the surface accuracy.

Figure 1



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